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PL-17/5B/08A (02-03)

Substitute for form 1449/PTO

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use as many sheets as necessary)

Sheet 1 of 2

Substitute for form 1449/PTO		Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(Use as many sheets as necessary)</i>		Application Number	10/722,806
		Filing Date	November 26, 2003
		First Named Inventor	Osamah M. El Rifai
		Art Unit	2829
		Examiner Name	Not Yet Assigned
Sheet	1	of	2
		Attorney Docket Number	MIT-135PUS

U. S. PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS

**Examiner
Signature**

Sue Ellis

Date Considered

16 AUG 05

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This collection of information is required by 37 CFR 1.97 and 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, Washington, DC 20231. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P. O. Box 1450, Alexandria, VA 22313-1450.

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Substitute for form 1449/PTO

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(Use as many sheets as necessary)

Sheet

12

of

2

Complete If Known	
Application Number	10/722,806
Filing Date	November 26, 2003
First Named Inventor	Osamah M. El Rifai
Art Unit	2829
Examiner Name	Not Yet Assigned
Attorney Docket Number	MIT-135PUS

OTHER PRIOR ART-NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
SYE		International Search Report for Application No. PCT/US2004/034390 dated April 12, 2005.	
SYE		SCHAFFER, T.E., ET AL., "Characterization and Optimization of the Detection Sensitivity of an Atomic Force Microscope for Small Cantilevers", Journal of Applied Physics AIP USA, vol. 84, no. 9, November 1, 1998, pages 4661-4666.	
SYE		KINDT, JOHANNES H. ET AL., Atomic Force Microscope Detector Drift Compensation by Correlation of Similar Traces Acquired at Different Setpoints", Review of Scientific Instruments, American Institute of Physics, USA, vol. 73, no. 6, June 2002, pages 2305-2307.	
SYE		AUMOND, B.D. ET AL., "High Precision Metrology by Means of a Novel Stereo Imaging Technique Based on atomic Force Microscopy", Proceeding of the SPIE - The International Society for Optical Engineering SPIE - INT. SOC. OPT. ENG USA, vol. 4344, February 26, 2001, pages 46-57.	
SYE		PINGALI, G.S. ET AL., "Restoration of Scanning Probe Microscope Images", Applications of Computer Vision, Proceeding, 1992, IEEE Workshop on Palm Springs, CA, USA, November 30 - December 2, 1992, Los Alamitos, CA, USA, IEEE COMPUT. SOC, US, November 30, 1992, pages 282-289.	

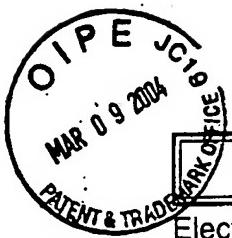
Examiner Signature	Suey Ellis	Date Considered	18JUL05
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1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.

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ELECTRONIC INFORMATION DISCLOSURE STATEMENT

Electronic Version v18

Stylesheet Version v18.0

Title of Invention	HEIGHT CALIBRATION OF SCANNING PROBE MICROSCOPE ACTUATORS						
Application Number:	10/722806 						
Confirmation Number:	8192						
First Named Applicant:	Osamah El Rifai						
Attorney Docket Number:	MIT-135PUS						
Art Unit:	2829						
Search string:	(5200617 or 5920067 or 6661004 or 5051646 or 5641897 or 5825670 or 6016684 or 5665905 or 5664512 or 5557156 or 5463897 or 5155359 or RE37299 or 5877497 or 5801381 or 5773824 or 6244103 or 5898106 or 5804708 or 5497656 or 6340858 or 5568003 or 5469734 or 5384507 or 6410907 or 6357285 or RE37404 or 5418363 or 5306919 or 5198715 or 5801390 or 5077473 or 5066858 or RE37560).pn.						
US Patent Documents							
Note: Applicant is not required to submit a paper copy of cited US Patent Documents							
init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
SYE	1	5200617	1993-04-06	Hayes et al.			
SYE	2	5920067	1999-07-06	Cresswell et al.			
SYE	3	6661004	2003-12-09	Aumond et al.			
SYE	4	5051646	1991-09-24	Elings et al.			
SYE	5	5641897	1997-06-24	Schuman			
SYE	6	5825670	1998-10-20	Chernoff et al.			
SYE	7	6016684	2000-01-25	Scheer et al.			
SYE	8	5665905	1997-09-09	Bartha et al.			
SYE	9	5664512	1997-07-01	Chernoff et al.			
SYE	10	5557156	1996-09-17	Elings			
SYE	11	5463897	1995-11-07	Prater et al.			
SYE	12	5155359	1992-10-13	Monahan			

SYE	13	RE37299	2001-07-31	Amer et al.
SYE	14	5877497	1999-03-02	Binnig et al.
SYE	15	5801381	1998-09-01	Flecha et al.
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SYE	17	6244103	2001-06-12	Berghaus et al.
SYE	18	5898106	1999-04-27	Babcock et al.
SYE	19	5804708	1998-09-08	Yamanaka et al.
SYE	20	5497656	1996-03-12	Kado et al.
SYE	21	6340858	2002-01-22	Jaenker
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SYE	24	5384507	1995-01-24	Takada et al.
SYE	25	6410907	2002-06-25	Cleveland et al.
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SYE	30	5198715	1993-03-30	Elings et al.
SYE	31	5801390	1992-01-14	Elings
SYE	32	5077473	1991-12-31	Elings et al.
SYE	33	5066858	1991-11-19	Elings et al.
SYE	34	RE37560	2002-02-26	Elings

Signature

Examiner Name	Date
<i>Suzan Ellis</i>	18JUL05